

**PATENT** 

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Bruce et al.

Examiner:

Choi, S.

Serial No.:

09/586,518

Group Art Unit:

2857

Filed:

June 2, 2000

Docket No.

AMDA.455PA

Title:

**RESISTIVITY ANALYSIS** 

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this communication is being deposited in the United States Postal Service, as first class mail, in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on September 10, 2002.

By: Frin M. Nichols

OFFICE ACTION RESPONSE AND AMENDMENT

Assistant Commissioner for Patents Washington, D.C. 20231

Sir:

In response to the non-final Office Action dated June 10, 2002, please consider the following amendment and remarks.

## In the Supplemental Declaration

Please use the attached supplemental declaration, in which the fields required under 37 CFR § 1.63 are now complete.

## In the Specification

Please replace the paragraph found at page 1, lines 8-15 of the specification as indicated below. The changes may be found on the attached sheet.

The following patent documents are related to the present invention and are hereby incorporated by reference in their entirety; these U.S. Patent Applications are identified by their Serial Nos. as follows: 09/034,546, filed on March 3, 1998 and entitled "Thermally-induced Voltage Alteration (TIVA)", now U.S. Patent No. 6,078,183; and 09/586,505, entitled "Method and Apparatus for Analyzing Functional Failures In Integrated Circuits" (Docket No.



